L Number	Hits	Search Text	DB	Time stamp
1	113	(memory and test$3 and defect$3 and repair$3) and ((buffer latch register) with (data information) with defect$3) and controller and (data with stor$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:07
2	2625656	1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:07
3	11	((memory and test$3 and defect$3 and repair$3) and ((buffer latch register) with (data information) with defect$3) and controller and (data with stor$3)) and (defect$3 same (temp$7 near3 (stor$3 buffer data)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:21
4	7	((memory and test$3 and defect$3 and repair$3) and ((buffer latch register) with (data information) with defect$3) and controller and (data with stor$3)) and (defect$3 with temp$7 with stor$3 with (data information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 20:14
-	24	memory and test$3 and defect$3 and (alternat$3 near3 (row column)) and address and (fail$3 fault$1) and (mov$3 near3 data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:52
-	5812	memory and test$3 and defect$3 and repair$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/11 16:51
-	0	(memory and test$3 and defect$3 and repair$3) and ((temp$3 near3 (stor$3 buffer)) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	641	(temp$3 near3 (stor$3 buffer)) with data	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	0	(memory and test$3 and defect$3 and repair$3) and (temp$3 with (stor$3 buffer) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54
-	291	(memory and test$3 and defect$3 and repair$3) and (test$3 with defect$3) and (repair$3 with (row column) with (address data))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:56
-	24	((memory and test$3 and defect$3 and repair$3) and (test$3 with defect$3) and (repair$3 with (row column) with (address data))) and (temp$7 with (stor$3 buffer))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 16:30
-	21	((memory and test$3 and defect$3 and repair$3) and (test$3 with defect$3) and (repair$3 with (row column) with (address data))) and ((alternat$3 adj2 (row column)) (every adj2 other adj2 (row column)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:05
-	26	"L24" and (mov$3 near3 data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 16:30

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–	2	((memory and test$3 and defect$3 and repair$3) and (test$3 with defect$3) and (repair$3 with (row column) with (address data))) and (temp$7 with (stor$3 buffer)) and (mov$3 near3 data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:56
–	1527	detect$3 near4 defect$3 near4 (cell transistor)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:56
–	400	test with (detect$3 near4 defect$3 near4 (cell transistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:57
–	508	test$3 with (detect$3 near4 defect$3 near4 (cell transistor))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:57
–	20	(test$3 with (detect$3 near4 defect$3 near4 (cell transistor))) and (repair$3 with (mov$3 replac$3 exchang$3) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:58
–	20	(test$3 with (detect$3 near4 defect$3 near4 (cell transistor))) and (repair$3 with (mov$3 replac$3 exchang$3 rearrang$3 re-arrang$3) with data)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 17:58

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